

Application/Control No.	Applicant(s)/Patent under Reexamination
10/773,668	KEIM ET AL.
Examiner	Art Unit

3661

CUONG H. NGUYEN

SEARCHED					
Class	Subclass	Date	Examiner		
701	51	4/11/2007	CHN		
239	585.2,585 .\	4/11/2007	CHN		
239	585.5	4/11/2007	CHN		
137	625	4/11/2007	CHN		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
701	51	4/12/2007	CHN	
239	585.2,585	4/11/2007	CHN	
91	459	4/11/2007	CHN	
B05B 1/30 G05D 16/20 F02M 51/00		4/12/2007	CHN	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
WEST/DERWENT on allowable subject matter and IDS references	4/11/2007	CHN	
IEEE Xplore	4/11/2007	CHN	
Dialog DataStar	4/11/2007	CHN	
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